

<b>Search Notes</b>  <b>*1059076</b>  <b>8*</b>	<b>Application/Control No.</b>  10590768	<b>Applicant(s)/Patent Under Reexamination</b>  JENSEN ET AL.
	<b>Examiner</b>  Young J Kim	<b>Art Unit</b>  1637

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Patent Databases (USPT, USPGP, EPO, JP0, DERWENT, IBM-TDB) - see enclosed for text search strategy	8/6/2009	/YJK/
Updated	12/8/2010	/YJK/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	Interference search history - see enclosed for strategy	12/8/2010	/YJK/

	/Young J Kim/ Primary Examiner.Art Unit 1637
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